

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)					Docket No.	Serial No.	
					APPM/5799	10/084,767	
SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT					Applicant	Confirmation No.:	
					Wang, et al.	Unknown	
(Use several sheets if necessary)					JUN 11 2002	Filing Date	Group
						02/26/2002	Unknown 162
U.S. Patent Documents							
*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
V	A1	4,058,430	11/15/77	Suntola et al.	156	6	11/25/75
	A2	4,389,973	6/28/83	Suntola et al.	153	72	12/11/83
	A3	4,413,022	11/1/83	Suntola et al.	43	2512	6/21/83
	A4	4,486,487	12/4/84	Skarp	4	21	4/25/84
	A5	4,767,494	8/30/88	Kobayashi et al.	1	60	9/19/88
	A6	4,806,321	2/21/89	Nishizawa et al.	43	243	7/21/89
	A7	4,813,846	3/21/89	Helms	43	743	4/29/89
	A8	4,829,022	5/9/89	Kobayashi et al.	43	103	12/9/88
	A9	4,834,831	5/30/89	Nishizawa et al.	153	61	9/4/89
	A10	4,838,983	6/13/89	Schumaker et al.	153	61	3/18/89
	A11	4,838,993	6/13/89	Aoki et al.	153	64	12/3/87
	A12	4,840,921	6/20/89	Matsumoto	43	89	6/30/88
	A13	4,845,049	7/4/89	Sunakawa	43	81	3/23/88
	A14	4,859,625	8/22/89	Nishizawa et al.	43	81	11/10/87
	A15	4,859,627	8/22/89	Sunakawa	43	81	7/1/88
	A16	4,861,417	8/29/89	Mochizuki et al.	153	61	3/23/88
	A17	4,876,218	10/24/89	Pessa et al.	43	103	9/27/88
	A18	4,917,556	4/17/90	Stark et al.	43	21	5/27/89
	A19	4,927,670	5/22/90	Erbil	43	2513	6/2/88
	A20	4,931,132	6/5/90	Aspnes et al.	153	60	10/27/88
	A21	4,951,601	8/28/90	Maydan, et al.	153	71	6/2/89
	A22	4,960,720	10/2/90	Shimbo	43	103	8/27/87
	A23	4,975,252	12/4/90	Nishizawa et al.	43	243	5/27/89
	A24	4,993,357	2/19/91	Scholz	113	71	12/21/89
	A25	5,000,113	3/19/91	Wang et al.	113	71	12/29/86
	A26	5,013,683	5/7/91	Petroff et al.	43	103	11/2/89
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U.S. Patent Documents							
*Examiner Initial	Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate	
A27	5,028,565	7/2/91	Chang, et al.	43	1	8/25/91	
A28	5,082,798	1/21/92	Arimoto	43	1	9/27/91	
A29	5,085,885	2/4/92	Foley et al.	43	36	9/10/91	
A30	5,091,320	2/25/92	Aspnes et al.	43	8	6/15/91	
A31	5,130,269	7/14/92	Kitahara et al.	43	1	4/25/91	
A32	5,166,092	11/24/92	Mochizuki et al.	43	1	10/30/91	
A33	5,173,474	12/22/92	Connell, et al.	50	1	3/11/91	
A34	5,186,718	2/16/93	Tepman et al.	29	2	4/15/91	
A35	5,205,077	4/27/93	Wittstock	51	1	8/28/91	
A36	5,225,366	7/6/93	Yoder	437	1	6/22/91	
A37	5,234,561	8/10/93	Randhawa et al.	204	1,38	8/25/91	
A38	5,246,536	9/21/93	Nishizawa et al.	156	6	3/10/91	
A39	5,250,148	10/5/93	Nishizawa et al.	156	6	11/12/91	
A40	5,254,207	10/19/93	Nishizawa et al.	156	6	11/30/91	
A41	5,256,244	10/26/93	Ackerman	156	6	2/10/91	
A42	5,259,881	11/9/93	Edwards, et al.	118	7	5/17/91	
A43	5,270,247	12/14/93	Sakuma et al.	437	1	7/8/92	
A44	5,278,435	1/11/94	Van Hove et al.	257	1	6/8/92	
A45	5,281,274	1/25/94	Yoder	118	6	2/4/91	
A46	5,286,296	2/15/94	Sato et al.	118	7	1/9/91	
A47	5,290,748	3/1/94	Knuutila et al.	502	2	7/16/91	
A48	5,294,286	3/15/94	Nishizawa et al.	156	6	1/12/91	
A49	5,296,403	3/22/94	Nishizawa et al.	437	1	10/23/91	
A50	5,300,186	4/5/94	Kitahara et al.	156	6	4/7/91	
A51	5,311,055	5/10/94	Goodman et al.	257	55	11/2/91	
A52	5,316,615	5/31/94	Copel	11	95	3/9/91	
Examiner _____				Date Considered <i>✓</i>			
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*Examiner Initials	Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate	
	A53 5,316,793	5/31/94	Wallace et al.	427	248-1	7/21/92	
	A54 5,330,610	7/19/94	Eres et al.	11	86	5/21/93	
	A55 5,336,324	8/9/94	Stall et al.	11	719	12/20/91	
	A56 5,338,389	8/16/94	Nishizawa et al.	11	89	4/21/93	
	A57 5,348,911	9/20/94	Jurgensen et al.	11	91	4/26/93	
	A58 5,374,570	12/20/94	Nasu et al.	43	40	8/19/93	
	A59 5,395,791	3/7/95	Cheng et al.	43	10	10/21/93	
	A60 5,438,952	8/8/95	Otsuka	1	84	1/31/94	
	A61 5,439,876	8/8/95	Graf et al.	5	44	8/16/95	
	A62 5,441,703	8/15/95	Jurgensen	4	12	3/29/94	
	A63 5,443,033	8/22/95	Nishizawa et al.	1	86	3/11/94	
	A64 5,443,647	8/22/95	Aucoin et al.	1	725 ME	7/11/94	
	A65 5,455,072	10/3/95	Bension et al.	43	2557	11/16/92	
	A66 5,458,084	10/17/95	Thorne et al.	1	85	12/9/93	
	A67 5,469,806	11/28/95	Mochizuki et al.	1	91	8/20/93	
	A68 5,480,818	1/2/96	Matsumoto et al.	43	40	2/9/96	
	A69 5,483,919	1/16/96	Yokoyama et al.	1	8	8/17/94	
	A70 5,484,664	1/16/96	Kitahara et al.	42	6	1/21/94	
	A71 5,503,875	4/2/96	Imai et al.	42	255.3	3/17/94	
	A72 5,521,126	5/28/96	Okamura et al.	43	15	6/22/94	
	A73 5,527,733	6/18/96	Nishizawa et al.	43	10	2/18/94	
	A74 5,532,511	7/2/96	Nishizawa et al.	25	7	3/27/95	
	A75 5,540,783	7/30/96	Eres et al.	11	755	5/26/94	
	A76 5,580,380	12/3/96	Liu, et al.	11	82	1/30/95	
	A77 5,601,651	2/11/97	Watabe	11	755	12/21/94	
	A78 5,609,689	3/11/97	Kato et al.	11	755	6/3/97	
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Examiner Initial	Examiner Unknown	Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
A79		5,616,181	4/1/97	Yamamoto et al.	11	723 ER	11/1/95
A80		5,637,530	6/10/97	Gaines et al.	11	1	6/10/96
A81		5,641,984	6/24/97	Aftergut et al.	25	43	8/19/94
A82		5,644,128	7/1/97	Wollnik et al.	25	25	8/20/94
A83		5,667,592	9/16/97	Boitnott et al.	11	71	4/10/96
A84		5,674,786	10/7/97	Turner et al.	43	22	6/5/97
A85		5,693,139	12/2/97	Nishizawa et al.	11	89	6/15/93
A86		5,695,564	12/9/97	Imahashi	11	71	8/3/98
A87		5,705,224	1/6/98	Murota et al.	42	248	1/31/95
A88		5,707,880	1/13/98	Aftergut et al.	43	3	1/17/97
A89		5,711,811	1/27/98	Suntola et al.	11	71	11/20/95
A90		5,730,801	3/24/98	Tepman et al.	11	719	8/23/94
A91		5,730,802	3/24/98	Ishizumi et al.	118	719	12/27/96
A92		5,747,113	5/5/98	Tsai	427	255	7/25/96
A93		5,749,974	5/12/98	Habuka et al.	118	723	7/13/95
A94		5,788,447	8/4/98	Yonemitsu et al.	414	217	8/5/98
A95		5,788,799	8/4/98	Steger, et al.	15	349	6/11/96
A96		5,796,116	8/18/98	Nakata et al.	25	66	7/25/96
A97		5,801,634	9/1/98	Young et al.	34	635	9/8/98
A98		5,807,792	9/15/98	Ilg et al.	43	756	12/1/96
A99		5,830,270	11/3/98	McKee et al.	11	106	8/5/98
A100		5,835,677	11/10/98	Li et al.	39	408	10/3/98
A101		5,851,849	12/22/98	Comizzoli et al.	42	38	5/22/97
A102		5,855,675	1/5/99	Doering et al.	1	71	3/3/98
A103		5,855,680	1/5/99	Soininen et al.	1	71	11/20/95
A104		5,856,219	1/5/99	Naito et al.	4	24	8/18/97
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	A105 5,858,102	1/12/99	Tsai	718	719	2/12/98
	A106 5,866,213	2/2/99	Foster et al.	437	573	7/19/97
	A107 5,866,795	2/2/99	Wang et al.	723	1,36	3/17/97
	A108 5,879,459	3/9/99	Gadgil et al.	113	715	8/29/97
	A109 5,882,165	3/16/99	Maydan et al.	433	217	9/10/97
	A110 5,882,413	3/16/99	Beaulieu et al.	113	719	7/11/97
	A111 5,904,565	5/18/99	Nguyen, et al.	433	687	7/17/97
	A112 5,916,365	6/29/99	Sherman	113	92	8/16/96
	A113 5,923,056	7/13/99	Lee et al.	237	192	3/12/98
	A114 5,923,985	7/13/99	Aoki et al.	433	301	1/14/97
	A115 5,925,574	7/20/99	Aoki et al.	433	31	4/10/92
	A116 5,928,389	7/27/99	Jevtic	233	250	10/21/96
	A117 5,942,040	8/24/99	Kim et al.	113	726	8/27/97
	A118 5,947,710	9/7/99	Cooper, et al.	433	63	6/16/97
	A119 5,972,430	10/26/99	DiMeo, Jr. et al.	433	255	11/26/97
	A120 6,001,669	12/14/99	Gaines et al.	433	102	7/21/92
	A121 6,015,590	1/18/00	Suntola et al.	423	255	11/26/95
	A122 6,025,627	2/15/00	Forbes et al.	257	321	5/29/98
	A123 6,036,773	3/14/00	Wang et al.	117	97	3/27/97
	A124 6,042,652	3/28/00	Hyun et al.	118	719	9/7/99
	A125 6,043,177	3/28/00	Falconer et al.	502	4	1/21/97
	A126 6,051,286	4/18/00	Zhao et al.	427	576	8/22/97
	A127 6,062,798	5/16/00	Muka	414	416	6/13/96
	A128 6,071,808	6/6/00	Merchant et al.	438	633	6/23/99
	A129 6,084,302	7/4/00	Sandhu	257	75	12/2/95
	A130 6,086,677	7/11/00	Umotoy et al.	118	7	6/16/98

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V	A131	6,110,556	8/29/00	Bang, et al.	42	64	10/11/97
	A132	6,113,977	9/5/00	Soininen et al.	42	64	9/11/97
	A133	6,117,244	9/12/00	Bang, et al.	11	715	3/26/98
	A134	6,124,158	9/26/00	Dautartas et al.	43	216	6/8/99
	A135	6,130,147	10/10/00	Major et al.	43	604	3/16/97
	A136	6,139,700	10/31/00	Kang et al.	20	192	9/30/98
	A137	6,140,237	10/31/00	Chan et al.	43	687	4/19/99
	A138	6,140,238	10/31/00	Kitch	43	687	4/21/99
	A139	6,143,659	11/7/00	Leem	43	688	8/27/98
	A140	6,144,060	11/7/00	Park et al.	29	310	7/31/98
	A141	6,158,446	12/12/00	Mohindra et al.	10	254	9/4/98
	A142	6,174,377	1/16/01	Doering, et al.	11	729	1/4/99
	A143	6,174,809	1/16/01	Kang, et al.	43	682	12/15/98
	A144	6,200,893	3/13/01	Sneh	43	685	3/1/98
	A145	6,203,613	3/20/01	Gates, et al.	11	104	10/12/99
	A146	6,206,967	3/27/01	Mak, et al.	11	666	6/14/00
	A147	6,207,302	3/27/01	Sugiura, et al.	42	690	3/2/98
	A148	6,248,605	6/19/01	Harkonen, et al.	43	29	6/2/99
	A149	6,270,572	8/7/01	Kim, et al.	11	93	8/9/99
	A150	6,271,148	8/7/01	Kao et al.	43	72	10/12/99
	A151	6,287,965	9/11/01	Kang, et al.	43	648	2/23/00
	A152	6,291,876	9/18/01	Stumborg, et al.	25	632	8/20/98
	A153	6,305,314	10/23/01	Sneh, et al.	11	733 R	12/12/99
	A154	6,306,216	10/23/01	Kim, et al.	11	735	7/12/00
	A155	6,316,098	11/13/01	Yitzchaik, et al.	43	30	3/23/99
	A156	2001/0042799	11/22/01	Kim, et al.	2	43	2/2/01
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	B1 196 27 017A1	1/9/97	DE	H01L	21/205	<input type="checkbox"/> <input checked="" type="checkbox"/>
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	B5 0 442 290 A1	2/14/91	EP	C07B	25/00	<input type="checkbox"/> <input type="checkbox"/>
	B6 0 344 352 A1	6/3/88	EP	H01L	39/20	<input type="checkbox"/> <input type="checkbox"/>
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	B22 63-085098	4/15/88	JP	C30B	25/00	<input checked="" type="checkbox"/> <input type="checkbox"/>
	B23 63-090833	4/21/88	JP	H01L	21/265	<input checked="" type="checkbox"/> <input type="checkbox"/>
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Examiner _____				Date Considered _____		
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.						

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)				Docket No. APPM/5799	Serial No. 10/084,767			
SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT				Applicant Wang, et al.	Confirmation No.: Unknown			
(Use several sheets if necessary)				Filing Date 02/26/2002	Group Unknown			
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Examiner				Date Considered				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 608, Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)				Docket No. APPM/5799	Serial No. 10/084,767		
SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT				Applicant Wang, et al.	Confirmation No.: Unknown		
(Use several sheets if necessary)				Filing Date 02/26/2002	Group Unknown		
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Examiner				Date Considered (M)			

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U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)					Docket No. APPM/5799	Serial No. 10/084,767		
SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT					Applicant Wang, et al.	Confirmation No.: Unknown		
(Use several sheets if necessary)					Filing Date 02/26/2002	Group <u>Unknown</u> 176		
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Examiner					Date Considered			

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U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)					Docket No. APPM/5799	Serial No. 10/084,767		
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(Use several sheets if necessary)					Filing Date 02/26/2002	Group Unknown		
Examiner Unknown					JUN 11 2002 PTO-505 PATENT & TRADEMARK OFFICE			
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(PTO Form 1449 modified)				APPM/5799	10/084,767
SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT				Applicant	Confirmation No.:
				Wang, et al.	Unknown
(Use several sheets if necessary)				Filing Date	Group
				02/26/2002	Unknown

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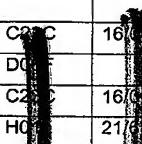
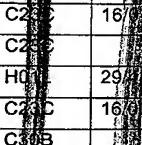
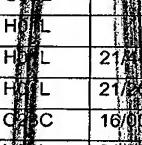
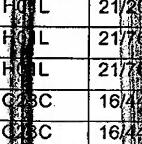
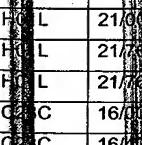
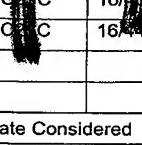
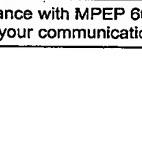
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SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT					Applicant Wang, et al.	Confirmation No.: Unknown		
(Use several sheets if necessary)					Filing Date 02/26/2002	Group <u>Unknown</u> 167		
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B195	01/40541 A1	6/7/01	WO	C23C	16/00		<input type="checkbox"/>	<input type="checkbox"/>
B196	01/66832 A2	9/13/01	WO	C23C	16/00		<input type="checkbox"/>	<input type="checkbox"/>
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Examiner Unknown.		JUN 11 2002 U.S. PATENT & TRADEMARK OFFICE O P E R A T I O N S	
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	C3	Yamaguchi, et al., "Atomic-layer chemical-vapor-deposition of silicon dioxide films with extremely low hydrogen content", <i>Appl. Surf. Sci.</i> , Vol. 130-132 (1998) , pp. 202-207	
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	C8	Ritala, et al., "Perfectly conformal TiN and Al ₂ O ₃ films deposited by atomic layer deposition", <i>Chemical Vapor Deposition</i> , Vol. 5(1) (January 1999), pp. 7-9	
	C9	Klaus, et al., "Atomically controlled growth of tungsten and tungsten nitride using sequential surface reactions", <i>Appl. Surf. Sci.</i> , Vol 162-163 (July 1999), pp. 479-491	
	C10	Klaus, et al., "Atomically controlled growth of tungsten and tungsten nitride using sequential surface reactions", <i>Fifth Int'l Symp. On Atomically Controlled Surfaces, Interfaces and Nanostructures</i> (July 6-9, 1999), Aix en Provence, France No page numbers	
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	C14	Ritala, et al. "Atomic Layer Epitaxy Growth of TiN Thin Films", <i>J. Electrochem. Soc.</i> , 142(8) (Aug. 1995), pp. 2731-737	
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C18	Min, et al., "Chemical Vapor Deposition of Ti-Si-N Films with Alternating Source Supply", <i>Mat., Res. Soc. Symp. Proc.</i> , Vol. 564 (Apr. 5, 1999), pp. 207-210		
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C30	NERAC.COM Retro Search: Atomic Layer Deposition / Epitaxy Aluminum Oxide Plasma, dated October 2, 2001 No page numbers		
C31	NERAC Search abstract of "Atomic Layer deposition of Ta and Ti for Interconnect Diffusion Barriers", by Rossnagel, et al., <i>J. Vac. Sci. & Tech.</i> , 18(4) (July 2000)		
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(Use several sheets if necessary)		Filing Date JUN 11 2002 Examiner Unknown	Group Unknown 162
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	C32	Abstracts of articles re atomic layer deposition No date or page numbers	
	C33	Abstracts of search results re atomic layer deposition, search dated January 24, 2002 No page numbers	
	C34	Abstracts of articles re atomic layer deposition and atomic layer nucleation No date or page numbers	
	C35	Abstracts of articles re atomic layer deposition and semiconductors and copper No date or page numbers	
	C36	Abstracts of articles – atomic layer deposition No date or page numbers	
	C37	NERAC Search – Atomic Layer Deposition, search dated October 16, 2001 No page numbers	
	C38	Bader, et al., "Integrated Processing Equipment", Solid State Technology, Cowan Pub., Vol. 33, No. 5 (May 1, 1990), pp. 149-154	
	C39	Choi, et al., "The effect of annealing on resistivity of low pressure chemical vapor deposited titanium diboride", J. Appl. Phys. 69(11) (June 1, 1991), pp. 7853-7861	
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	C42	"Applications of Integrated processing", Solid State Technology, US, Cowan Pub., Vol 37, No. 12 (December 1, 1994), pp. 45-47	
	C43	Kitigawa, et al., "Hydrogen-mediated low temperature epitaxy of Si in plasma-enhanced chemical vapor deposition", Applied Surface Science (2000), pp. 30-34	
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT					Applicant Wang, et al.	Confirmation No.: 3478		
(Use several sheets if necessary)					Filing Date February 26, 2002	Group 1762		
Examiner Unknown								
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	A1	6,534,395	03/18/02	Werkhoven, et al.	438	6	03/18/01	
	A2	6,511,539	01/28/03	Raaijmakers	1	1	09/23/99	
	A3	6,482,740	11/19/02	Soininen, et al.	4	6	05/13/01	
	A4	6,482,733	11/19/02	Raaijmakers, et al.	4	6	04/23/01	
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	A6	6,475,910	11/05/02	Sneh	4	6	09/23/00	
	A7	6,475,276	11/05/02	Elers, et al.	1	8	10/16/00	
	A8	6,468,924	10/22/02	Lee, et al.	4	7	05/30/01	
	A9	6,451,695	09/17/02	Sneh	4	6	12/23/00	
	A10	6,447,933	09/10/02	Wang, et al.	4	6	04/23/01	
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	A12	6,423,619	07/23/02	Grant, et al.	4	5	11/03/01	
	A13	6,420,189	07/16/02	Lopatin	438	2	04/23/01	
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VHL	C1	Yang, et al. "Atomic Layer Deposition of Tungsten Film from WF ₆ /B ₂ H ₆ : Nucleation Layer for Advanced Semiconductor Device," Conference Proceedings ULSI XVII (2002) Materials Research Society no page numbers						
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	C3							
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(Use several sheets if necessary)				Filing Date February 26, 2002	Group 1762	
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	A2 6,399,491	06/04/02	Jeon, et al.	438	610	04/06/01
	A3 6,391,803	05/21/02	Kim, et al.	438	71	06/20/01
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	B2 2000-178735	06/27/00	JP	C21C	16/00	<input type="checkbox"/> YES <input type="checkbox"/> NO
	B3 1,167,569	01/02/02	EP	C21C	16/00/15	<input type="checkbox"/> YES <input type="checkbox"/> NO
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U.S. Patent Documents <table border="1"> <thead> <tr> <th>*Examiner Initial</th> <th>Document Number</th> <th>Issue Date</th> <th>Applicant(s) Name</th> <th>Class</th> <th>Subclass</th> <th>Filing Date If Appropriate</th> </tr> </thead> <tbody> <tr><td>A1</td><td>5,306,666</td><td>04/26/94</td><td>Iuzmi</td><td>47</td><td>19</td><td>07/21/93</td></tr> <tr><td>A2</td><td>2003/0082296</td><td>05/01/03</td><td>Elers, et al.</td><td>47</td><td>9</td><td>09/11/02</td></tr> <tr><td>A3</td><td>2003/0072975</td><td>04/17/03</td><td>Shero, et al.</td><td>48</td><td>70</td><td>09/26/02</td></tr> <tr><td>A4</td><td>2003/0049942</td><td>03/13/03</td><td>Haukka, et al.</td><td>48</td><td>7</td><td>08/22/02</td></tr> <tr><td>A5</td><td>2003/0032281</td><td>02/13/03</td><td>Werkhoven, et al.</td><td>48</td><td>6</td><td>09/23/02</td></tr> <tr><td>A6</td><td>2003/0031807</td><td>02/13/03</td><td>Elers, et al.</td><td>47</td><td>56</td><td>09/11/02</td></tr> <tr><td>A7</td><td>2003/0013320</td><td>01/16/03</td><td>Kim, et al.</td><td>48</td><td>7</td><td>05/31/01</td></tr> <tr><td>A8</td><td>2002/0197402</td><td>12/26/02</td><td>Chiang, et al.</td><td>47</td><td>2539</td><td>08/01/02</td></tr> <tr><td>A9</td><td>2002/0187631</td><td>12/12/02</td><td>Kim, et al.</td><td>48</td><td>63</td><td>12/01/01</td></tr> <tr><td>A10</td><td>2002/0187256</td><td>12/12/02</td><td>Elers, et al.</td><td>47</td><td>99</td><td>07/31/02</td></tr> <tr><td>A11</td><td>2002/0182320</td><td>12/05/02</td><td>Leskela, et al.</td><td>47</td><td>25</td><td>03/16/02</td></tr> <tr><td>A12</td><td>2002/0164423</td><td>11/07/02</td><td>Chiang, et al.</td><td>47</td><td>2528</td><td>05/13/02</td></tr> <tr><td>A13</td><td>2002/0164421</td><td>11/07/02</td><td>Chiang, et al.</td><td>47</td><td>201</td><td>05/13/02</td></tr> <tr><td>A14</td><td>2002/0162506</td><td>11/07/02</td><td>Sneh, et al.</td><td>48</td><td>7</td><td>06/18/02</td></tr> <tr><td>A15</td><td>2002/0155722</td><td>10/24/02</td><td>Satta, et al.</td><td>48</td><td>7</td><td>04/15/02</td></tr> <tr><td>A16</td><td>2002/0146511</td><td>10/10/02</td><td>Chiang, et al.</td><td>47</td><td>201</td><td>10/24/01</td></tr> <tr><td>A17</td><td>2002/0144657</td><td>10/10/02</td><td>Chiang, et al.</td><td>48</td><td>7</td><td>10/03/01</td></tr> <tr><td>A18</td><td>2002/0144655</td><td>10/10/02</td><td>Chiang, et al.</td><td>48</td><td>7</td><td>10/24/01</td></tr> <tr><td>A19</td><td>2002/0121697</td><td>09/05/02</td><td>Marsh</td><td>2</td><td>7</td><td>04/30/02</td></tr> <tr><td>A20</td><td>2002/0117399</td><td>08/29/02</td><td>Chen, et al.</td><td>2</td><td>1</td><td>02/23/01</td></tr> <tr><td>A21</td><td>2002/0109168</td><td>08/15/02</td><td>Kim, et al.</td><td>2</td><td>2</td><td>01/30/02</td></tr> <tr><td>A22</td><td>2002/0106846</td><td>08/08/02</td><td>Seutter, et al.</td><td>4</td><td>2</td><td>02/22/01</td></tr> <tr><td>A23</td><td>2002/0105088</td><td>08/08/02</td><td>Yang, et al.</td><td>2</td><td>7</td><td>10/11/01</td></tr> <tr><td>A24</td><td>2002/0104481</td><td>08/08/02</td><td>Chiang, et al.</td><td>1</td><td>71</td><td>03/19/01</td></tr> <tr><td>A25</td><td>2002/0094689</td><td>07/18/02</td><td>Park</td><td>4</td><td>6</td><td>03/07/02</td></tr> </tbody> </table>							*Examiner Initial	Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate	A1	5,306,666	04/26/94	Iuzmi	47	19	07/21/93	A2	2003/0082296	05/01/03	Elers, et al.	47	9	09/11/02	A3	2003/0072975	04/17/03	Shero, et al.	48	70	09/26/02	A4	2003/0049942	03/13/03	Haukka, et al.	48	7	08/22/02	A5	2003/0032281	02/13/03	Werkhoven, et al.	48	6	09/23/02	A6	2003/0031807	02/13/03	Elers, et al.	47	56	09/11/02	A7	2003/0013320	01/16/03	Kim, et al.	48	7	05/31/01	A8	2002/0197402	12/26/02	Chiang, et al.	47	2539	08/01/02	A9	2002/0187631	12/12/02	Kim, et al.	48	63	12/01/01	A10	2002/0187256	12/12/02	Elers, et al.	47	99	07/31/02	A11	2002/0182320	12/05/02	Leskela, et al.	47	25	03/16/02	A12	2002/0164423	11/07/02	Chiang, et al.	47	2528	05/13/02	A13	2002/0164421	11/07/02	Chiang, et al.	47	201	05/13/02	A14	2002/0162506	11/07/02	Sneh, et al.	48	7	06/18/02	A15	2002/0155722	10/24/02	Satta, et al.	48	7	04/15/02	A16	2002/0146511	10/10/02	Chiang, et al.	47	201	10/24/01	A17	2002/0144657	10/10/02	Chiang, et al.	48	7	10/03/01	A18	2002/0144655	10/10/02	Chiang, et al.	48	7	10/24/01	A19	2002/0121697	09/05/02	Marsh	2	7	04/30/02	A20	2002/0117399	08/29/02	Chen, et al.	2	1	02/23/01	A21	2002/0109168	08/15/02	Kim, et al.	2	2	01/30/02	A22	2002/0106846	08/08/02	Seutter, et al.	4	2	02/22/01	A23	2002/0105088	08/08/02	Yang, et al.	2	7	10/11/01	A24	2002/0104481	08/08/02	Chiang, et al.	1	71	03/19/01	A25	2002/0094689	07/18/02	Park	4	6	03/07/02
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT JUN 3 0 2003					Applicant Wang, et al.	Confirmation No.: 3478	
(Use several sheets if necessary)					Filing Date February 26, 2002	Group 1762	
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*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
	A1	2002/0090829	07/11/02	Sandhu, et al.	43	76	01/30/02
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	A16	2002/0016084	02/07/02	Todd	43	1	04/26/01
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	A25	2001/0009695	07/26/01	Saanila, et al.	27	39	01/23/01
	A26	2001/0002280	05/31/01	Sneh	42	28	12/22/00
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